



COMPLIANCE PROGRAM

TEST REPORT

USB 2.0 Test Report For Peripheral

Company Name: ID TECH

VID (Dec or Hex): 0ACD The VID for the company who apply the USB-IF logo.

Model Name: IDEM-851P

Product Type: Augusta S

Report Date: 2016/08/11

Test Result: **PASS**

Tester: Vicky Xu

Authorized Signature: Howard Chang



Legal Disclaimer

1. TEST RESULT IS VALID ONLY TO THE ORIGINAL TESTED DEVICE MODEL. ALLION RESERVES THE RIGHT TO PROHIBIT OTHERS TO DISTORT, ISOLATE, FALSIFY, COPIED AND/OR BY ANY PROCESS TO CHANGE THE CONTENT OF THIS TEST REPORT UNLESS IT IS PRIOR APPROVED BY ALLION.



Company Information:

Company

Company Name: ID TECH
Company Address: 10721 Walker Street Cypress, CA 90630

Technical Contact

Name: Zhu Kefeng
Phone Number: 021-64707052-347
E-Mail: kefengz@idtechproducts.com.cn
FAX Number: 021-64707052-303

Marketing Contact

Name: Zhu Kefeng
Phone Number: 021-64707052-331
E-Mail: kefengz@idtechproducts.com.cn
FAX Number: 021-64707052-303



High Speed & Basic Speed Compliance Tests

A4.4: Device High-speed Signal Quality Pass Fail N/A

These tests measure the ability of transmitters to do valid high speed signaling. High speed signal quality is measured on upstream ports. A high speed scope with differential probes is used. Signaling data is captured with the scope and then translated to an eye pattern. The signal quality eye patterns obtained from the measurements must agree with the transmit eye patterns in the USB 2.0 Specification.

Connector Type: _____ (Tethered means no standard B or special B connector)

EL_2: Transmitter Data Rate Pass Fail N/A

EL_4: Eye Pattern (Template 1) Pass Fail N/A

EL_5: Eye Pattern (Template 2) Pass Fail N/A

EL_6: Rising and Falling Time Pass Fail N/A

EL_7: Monotonic Data Transition Pass Fail N/A

A4.5: Device Packet Parameters Pass Fail N/A

This test measures the amount of time it takes hosts and devices to respond. It also verifies device generated SYNCs and EOPs.

EL_21: bit Pass Fail N/A
(32bit)

EL_22-Step1: bit Pass Fail N/A
(>=8bit and <=192bit)

EL_22-Step2: bit Pass Fail N/A
(>=8bit and <=192bit)

EL_25: bit Pass Fail N/A
(8bit)

A4.6: Device CHIRP Timing Pass Fail N/A

This test examines the basic timings and voltages of both upstream ports during the speed detection protocol. (Device reset from Full Speed)

EL_28: Pass Fail N/A
(>=2.5us and <=6ms)

EL_29: ms Pass Fail N/A
(>=1ms and <=7ms)

EL_31: us Pass Fail N/A
(<=500us)



A4.7: Device Suspend/Resume/Reset timing Pass Fail N/A

This test verifies that a device can be suspended and resumed while operating in high speed and also that the device can be reset from the suspended state.

EL_38: ms Pass Fail N/A
($\geq 3\text{ms}$ and $\leq 3.125\text{ms}$)

EL_39: Pass Fail N/A

EL_40: Pass Fail N/A

EL_27: ms Pass Fail N/A
($\geq 3.1\text{ms}$ and $\leq 6\text{ms}$)

EL_28: Pass Fail N/A
($\geq 2.5\mu\text{s}$ and $\leq 6\text{ms}$)

A4.8: Device Test J/K, SE0_NAK Pass Fail N/A

The USB-IF no longer requires EL_8: Test_J and Test_K to be performed as a condition for USB Certification. Measurement of EL_9: Test_J, Test_K and SE0 are still a requirement for certification. EL_9 is defined in the USB 2.0 Test Specification and measures the data line voltage when not driven. For detail information please reference as below link:

EL_9

Test Mode	Voltage (mV)
SE0_NAK D+	
SE0_NAK D-	
Test J D-	
Test K D+	

(-20mV to 20mV)



A4.9: Device Receiver Sensitivity

Pass Fail N/A

These tests check the receive characteristics of upstream ports

EL_18 Pass Fail N/A

EL_17 Positive: + mV Pass Fail N/A
($\leq +200\text{mV}$)

EL_17 Negative: - mV Pass Fail N/A
($\geq -200\text{mV}$)

EL_16 Positive: + mV Pass Fail N/A
($\geq +100\text{mV}$)

EL_16 Negative: - mV Pass Fail N/A
($\leq -100\text{mV}$)

Basic Speed Signal Quality Test Result

Pass Fail

Connector Type: Tethered (Tethered means no standard B or special B connector)

Basic Speed Upstream Signal Quality: Pass Fail

Inrush Current Test: Pass Fail

Back Voltage Test Result

Pass Fail

Enumerate before / after

Pin	Voltage (mV)	
D+	0	0
D-	0	0
V _{Bus}	0	0

(All values $\leq 400\text{mV}$)

Miscellaneous:

Pass Fail

Bypass Capacitance Check: Pass Fail

BC 1.2 Implemented Check: Support N/A

If the upstream port has BC 1.2 capability, all items of BC 1.2 Portable Device category should be tested under this port for USB-IF certification.



Frameworks Test Result (USB30CV)

Pass **Fail**

All USB peripherals are required to enumerate on a SuperSpeed host controller and pass all applicable tests within USB30CV. Failure framework test in USB30CV will prevent certification.

High-Speed:

VID: _____ PID: _____

Chapter 9 Test: **Pass** **Fail** **N/A**

Interface: _____ MAX Power: _____ mA Remote Wakeup: _____

MSC Class Test: **Pass** **Fail** **N/A**

UVC Class Test: **Pass** **Fail** **N/A**

HID Class Test: **Pass** **Fail** **N/A**

Basic-Speed:

VID: 0acd PID: 3920

Chapter 9 Test: **Pass** **Fail**

Interface: 1 MAX Power: 200 mA Remote Wakeup: N/A

MSC Class Test: **Pass** **Fail** **N/A**

UVC Class Test: **Pass** **Fail** **N/A**

HID Class Test: **Pass** **Fail** **N/A**



Power Current Test Result

Pass Fail

High-Speed: _____ Pass Fail N/A

Unconfiguration Power: _____ mA
($\leq 100\text{mA}$)

Configuration Power: _____ mA
($\leq \text{Max Power} \leq 100\text{mA}$ for Low Power)
($\leq \text{Max Power} \leq 500\text{mA}$ for High Power)

Suspend Mode Power without Remote Wakeup: _____ μA
Suspend Mode Power with Remote Wakeup Enabled: _____ μA
Suspend Mode Power with Remote Wakeup Disabled: _____ μA
($\leq 2500\mu\text{A}$ for Self Power Hub or Non Compound Device)
($\leq 12500\mu\text{A}$ for Bus Power Hub or Compound Device)

Powered' State Suspend Mode Power: _____ μA
($\leq 2500\mu\text{A}$ for not Supporting USB Battery Charging)
($\leq 100\text{mA}$ for Supporting USB Battery Charging)

Operating Power: _____ mA
($\leq \text{Max Power} \leq 100\text{mA}$ for Low Power)
($\leq \text{Max Power} \leq 100\text{mA}$ for Self Power)
($\leq \text{Max Power} \leq 500\text{mA}$ for High Power)

Basic-Speed: High Powered Device Pass Fail

Unconfiguration Power: 54 mA
($\leq 100\text{mA}$)

Configuration Power: 54 mA
($\leq \text{Max Power} \leq 100\text{mA}$ for Low Power)
($\leq \text{Max Power} \leq 500\text{mA}$ for High Power)

Suspend Mode Power without Remote Wakeup: 954 μA
Suspend Mode Power with Remote Wakeup Enabled: N/A μA
Suspend Mode Power with Remote Wakeup Disabled: N/A μA
($\leq 2500\mu\text{A}$ for Self Power Hub or Non Compound Device)
($\leq 12500\mu\text{A}$ for Bus Power Hub or Compound Device)

Powered' State Suspend Mode Power: 960 μA
($\leq 2500\mu\text{A}$ for not Supporting USB Battery Charging)
($\leq 100\text{mA}$ for Supporting USB Battery Charging)

Operating Power: 53 mA
($\leq \text{Max Power} \leq 100\text{mA}$ for Low Power)
($\leq \text{Max Power} \leq 100\text{mA}$ for Self Power)
($\leq \text{Max Power} \leq 500\text{mA}$ for High Power)



Interoperability Test Overall Result

Pass Fail

Operating System: Win10

EHCI Host Controller:

Enumeration and Driver installation

Pass Fail

Check operation of device

Pass Fail

Interoperability – Operate all devices

Pass Fail

Hot plug test – A Plug

Pass Fail

Hot plug test – B Plug

Pass Fail N/A

Warm Boot test

Pass Fail

Remote Wake-up Test

Pass Fail N/A

S3 Active Standby Test

Pass Fail

S3 Active Standby Resume Test

Pass Fail

Root Port Test

Pass Fail

S4 Active Hibernate Test

Pass Fail

S4 Active Hibernate Resume Test

Pass Fail



Battery Charging 1.2 Compliance Test

<u>Portable Device (PD)</u>	<input type="checkbox"/> Pass	<input type="checkbox"/> Fail	<input checked="" type="checkbox"/> N/A
B-UUT Initial Power-up Test	<input type="checkbox"/> Pass	<input type="checkbox"/> Fail	<input checked="" type="checkbox"/> N/A
Data Contact Detect Test – With Current Source	<input type="checkbox"/> Pass	<input type="checkbox"/> Fail	<input checked="" type="checkbox"/> N/A
Data Contact Detect Test – No Current Source	<input type="checkbox"/> Pass	<input type="checkbox"/> Fail	<input checked="" type="checkbox"/> N/A
DCP Detection Test	<input type="checkbox"/> Pass	<input type="checkbox"/> Fail	<input checked="" type="checkbox"/> N/A
CDP Detection Test	<input type="checkbox"/> Pass	<input type="checkbox"/> Fail	<input checked="" type="checkbox"/> N/A
SDP Detection Test	<input type="checkbox"/> Pass	<input type="checkbox"/> Fail	<input checked="" type="checkbox"/> N/A
ACA-Dock Detection Test	<input type="checkbox"/> Pass	<input type="checkbox"/> Fail	<input checked="" type="checkbox"/> N/A
ACA-A Detection Test	<input type="checkbox"/> Pass	<input type="checkbox"/> Fail	<input checked="" type="checkbox"/> N/A
ACA-B Detection Test	<input type="checkbox"/> Pass	<input type="checkbox"/> Fail	<input checked="" type="checkbox"/> N/A
ACA-C Detection Test	<input type="checkbox"/> Pass	<input type="checkbox"/> Fail	<input checked="" type="checkbox"/> N/A
ACA-GND Detection Test	<input type="checkbox"/> Pass	<input type="checkbox"/> Fail	<input checked="" type="checkbox"/> N/A
Common Mode Test - Full Speed	<input type="checkbox"/> Pass	<input type="checkbox"/> Fail	<input checked="" type="checkbox"/> N/A
Common Mode Test - High Speed	<input type="checkbox"/> Pass	<input type="checkbox"/> Fail	<input checked="" type="checkbox"/> N/A
Dead Battery Provision Test	<input type="checkbox"/> Pass	<input type="checkbox"/> Fail	<input checked="" type="checkbox"/> N/A



More Detail Test Result:

1. Basic Speed Upstream Signal Quality: Pass

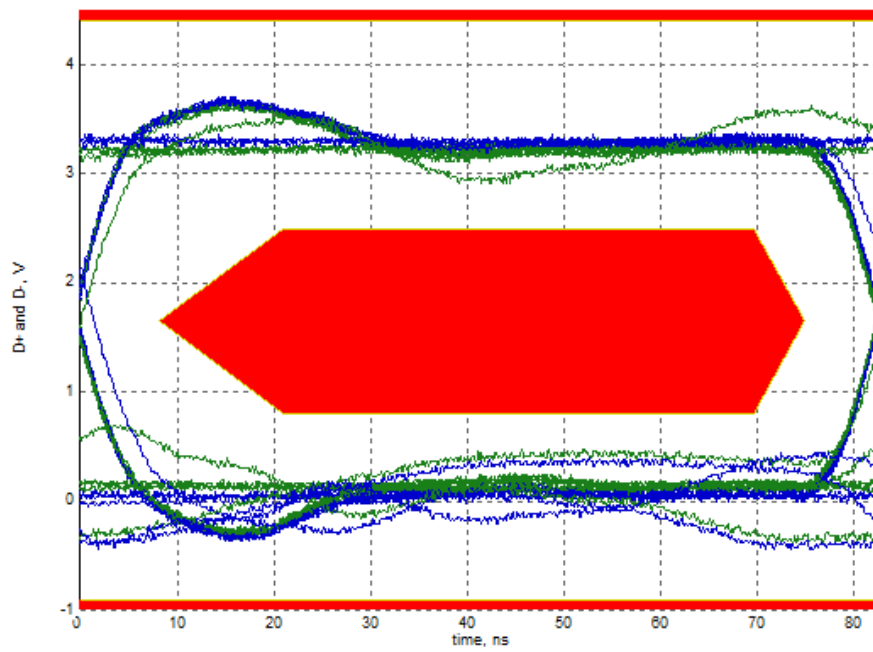
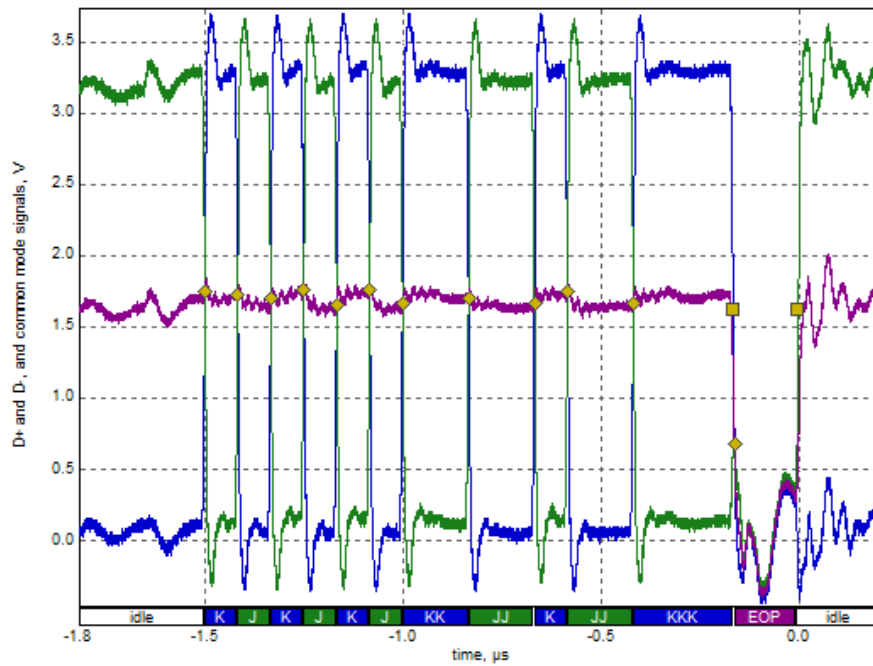
- Overall result: pass!
- Sync result:
sync passes
- Signal eye:
eye passes
- EOP width: 165.31 ns
EOP width passes
- Measured signaling rate: 11.9973 MHz
signal rate passes
- Edge Monotonicity: 20 mV
Monotonic Edge passes
- Crossover voltage range: 0.68 V to 1.76 V, mean crossover 1.62 V
(first crossover at 1.75 V, 11 other differential crossovers checked)
crossover voltages pass
- Consecutive jitter range: -573.063 ps to -398.480 ps, RMS jitter 475.141 ps
- Paired JK jitter range: -151.667 ps to 56.250 ps, RMS jitter 84.445 ps
- Paired KJ jitter range: -68.750 ps to 66.250 ps, RMS jitter 56.274 ps
jitter passes

Additional Information

- Rising Edge Rate: 345.16 V/us (Equivalent risetime = 7.65 ns)
- Falling Edge Rate: 312.01 V/us (Equivalent falltime = 8.46 ns)
- Edge Rate Match: 10.09% (limit +/-10%)



SignalData and Eye

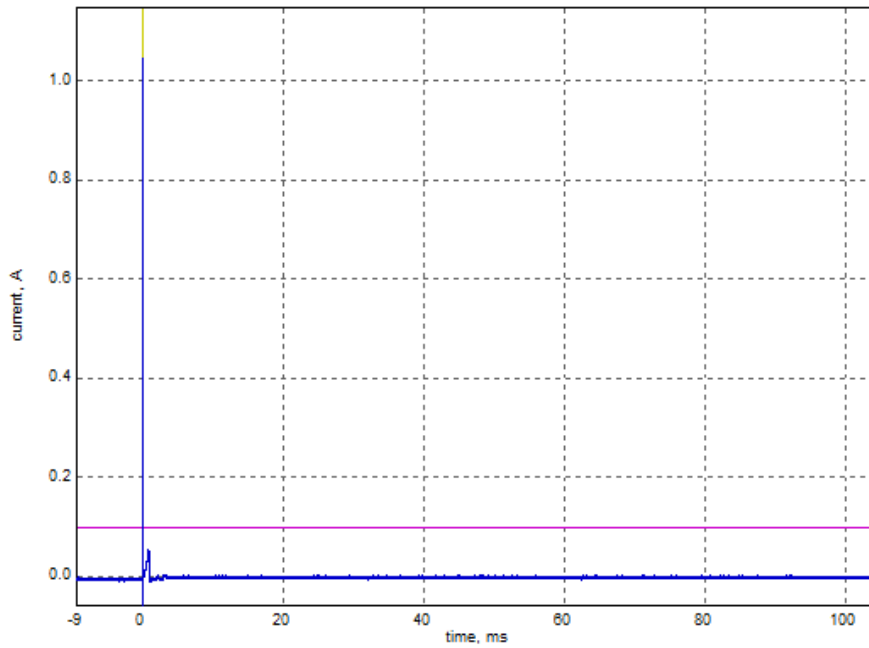




2. Inrush Current: Pass

- Overall result: pass!
- Inrush at 5.000 V: 10.3299 μ C
Inrush passes
- Region 1 Start: 0.00000 ms - End: 0.124 ms = 10.33 μ C

Hot Plug (Attach) Current Draw





Test Procedure Reference:

1. Universal Serial Bus Implementers Forum Device High-speed Electrical Test Procedure For Tektronix Test Equipment, version: 1.5
2. Universal Serial Bus Implementers Forum Full and Low Speed Electrical and Interoperability Compliance Test Procedure, Version: 1.3
3. USB-IF Compliance Update Page---Interoperability Gold Tree Update
<http://compliance.usb.org/resources/GoldSuite%20Test%20Procedure.pdf>
4. USB Battery Charging 1.2 Compliance Plan, Revision: 1.1

Notice: Test result is valid only to the original tested device model. The content of test report may not be copied or re-transmitted (except for the entire report) unless it is prior approved by Allion.